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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
10/808,499	03/25/2004	Hidekazu Miyairi	0756-7275	5721	
31780 ERIC ROBINS	7590 04/12/2007 SON		EXAMINER		
PMB 955			WEST, JEFFREY R		
21010 SOUTHBANK ST. POTOMAC FALLS, VA 20165  ART UNIT 2857		PAPER NUMBER			
			2857		
			· .		
			MAIL DATE	DELIVERY MODE	
			04/12/2007	PAPER	

Please find below and/or attached an Office communication concerning this application or proceeding.

# Advisory Action Before the Filing of an Appeal Brief

Applicant(s)
MIYAIRI ET AL.
Art Unit
2857

	Jeπrey R. West	2857	
The MAILING DATE of this communication appe	ars on the cover sheet with the c	orrespondence add	ress
THE REPLY FILED 30 March 2007 FAILS TO PLACE THIS AP	PLICATION IN CONDITION FOR	ALLOWANCE.	
1.  The reply was filed after a final rejection, but prior to or on this application, applicant must timely file one of the follow places the application in condition for allowance; (2) a No a Request for Continued Examination (RCE) in compliance time periods:	ving replies: (1) an amendment, aft tice of Appeal (with appeal fee) in	fidavit, or other evider compliance with 37 C	rce, which FR 41.31; or (3)
a) $\boxtimes$ The period for reply expires $3$ months from the mailing date	of the final rejection.		
b) The period for reply expires on: (1) the mailing date of this A no event, however, will the statutory period for reply expire a Examiner Note: If box 1 is checked, check either box (a) or (TWO MONTHS OF THE FINAL REJECTION. See MPEP 7)	ater than SIX MONTHS from the mailin b). ONLY CHECK BOX (b) WHEN THI	g date of the final rejecti	on.
Extensions of time may be obtained under 37 CFR 1.136(a). The date nave been filed is the date for purposes of determining the period of exunder 37 CFR 1.17(a) is calculated from: (1) the expiration date of the set forth in (b) above, if checked. Any reply received by the Office later may reduce any earned patent term adjustment. See 37 CFR 1.704(b) NOTICE OF APPEAL	tension and the corresponding amount shortened statutory period for reply orig than three months after the mailing da	of the fee. The approprinally set in the final Offi	ate extension fee ce action; or (2) as
<ol> <li>The Notice of Appeal was filed on A brief in comp filing the Notice of Appeal (37 CFR 41.37(a)), or any exter a Notice of Appeal has been filed, any reply must be filed</li> </ol>	nsion thereof (37 CFR 41.37(e)), to	avoid dismissal of th	
AMENDMENTS			
3. The proposed amendment(s) filed after a final rejection,  (a) They raise new issues that would require further co  (b) They raise the issue of new matter (see NOTE belo	nsideration and/or search (see NO w);	TE below);	
<ul><li>(c) They are not deemed to place the application in bet appeal; and/or</li></ul>	ter form for appear by materially re	ducing or simplifying	ine issues ioi
(d) They present additional claims without canceling a	corresponding number of finally rej	ected claims.	
NOTE: See Continuation Sheet. (See 37 CFR 1.1	16 and 41.33(a)).		
4. The amendments are not in compliance with 37 CFR 1.13	21. See attached Notice of Non-Co	mpliant Amendment	(PTOL-324).
5. Applicant's reply has overcome the following rejection(s)	<u>:</u> .		
<ol> <li>Newly proposed or amended claim(s) would be al non-allowable claim(s).</li> </ol>	lowable if submitted in a separate,	timely filed amendme	ent canceling the
7. For purposes of appeal, the proposed amendment(s): a) how the new or amended claims would be rejected is proposed. The status of the claim(s) is (or will be) as follows:		Il be entered and an e	explanation of
Claim(s) allowed: Claim(s) objected to:			
Claim(s) rejected:			
Claim(s) withdrawn from consideration:			
AFFIDAVIT OR OTHER EVIDENCE			
<ol> <li>The affidavit or other evidence filed after a final action, bu because applicant failed to provide a showing of good and was not earlier presented. See 37 CFR 1.116(e).</li> </ol>	d sufficient reasons why the affiday	vit or other evidence is	necessary and
2. The affidavit or other evidence filed after the date of filing entered because the affidavit or other evidence failed to of showing a good and sufficient reasons why it is necessary	vercome <u>all</u> rejections under appe y and was not earlier presented. S	al and/or appellant fai see 37 CFR 41.33(d)(1	ls to provide a
10. The affidavit or other evidence is entered. An explanation	n of the status of the claims after e	ntry is below or attach	ied.
REQUEST FOR RECONSIDERATION/OTHER		re e n	
<ol> <li>The request for reconsideration has been considered bu <u>See Continuation Sheet.</u></li> </ol>		n condition for allowar	ice because:
12. Note the attached Information Disclosure Statement(s).	(PTO/SB/08) Paper No(s)		
13.		EXAMENER	Ź 1 <del>.4</del>
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#### Continuation of 3:

The proposed amendments to independent claims 1, 3, 26, and 28 specifying the directions of the rows and columns, the calculation of average values of corrected saturations, obtaining an approximate line from relations between positions in the Y direction, and the fluctuations being obtained from relations between the approximate line and the average values, as well as the proposed amendment to claim 11, are considered to be new issues that would require additional search and/or consideration.

#### Continuation of 11:

As an initial matter, the Examiner maintains the withdrawal of claim 83 as Applicant's Response to Election filed November 07, 2005, indicated that claim 83 was not elected and the Non-Final Office Action mailed January 26, 2006, indicated that claim 83 was withdrawn. It is also noted that claim 83 is a duplicate of its parent claim 77.

#### Applicant argues:

Ozawa merely discloses an XO position having a maximum of added value derived luminance values to specify the boundary line in Figure 4. That is, Ozawa appears to teach electing an X coordinate position of "154" having a position XO (a peak position) having the maximum of added value derivated luminance values (or a mean value) to specify the boundary line (Figure 4, column 8 lines 3-20). However, Ozawa does not teach or suggest testing the crystallinity of a semiconductor film, of which the crystallinity is improved, using a fluctuation obtained from relations between an approximate line and average values.

The Examiner asserts that the since the proposed amendments are not being entered, the limitation in question requires "testing the crystallinity of the semiconductor film, of which the crystallinity is improved with a fluctuation obtained from the approximate line and the average value."

With Tsumura disclosing testing the crystallinity of a semiconductor film, of which the crystallinity is improved, Ozawa is relied upon for teaching image discriminations using a fluctuation obtained from the approximate line and the average value.

#### Ozawa discloses

In each of the rows corresponding to X coordinate positions "151," "152," . . . of the unit blocks arranged in Y direction, that is, in each of the row with peak values positioned therein on the image and the rows adjacent thereto, the luminances of unit blocks are added.

FIG. 4C represents added luminance values graphically with respect to each of the rows arranged in Y direction. In each of the rows of X coordinate positions "151," "152," "153," luminance values are added and then compared for each row. In the same figure, if a curved line connecting the added values is drawn, a peak position (a predicted peak position) of that curved line can be specified to be the position of the boundary line of the slider edge portion X0.

Alternatively, there may be adopted a method wherein, in each of the rows extending in Y direction, a mean luminance value in unit blocks pixels) is determined to draw the curved line shown in FIG. 4C, and a peak value of the curved line is specified to be the position of the edge portion X0. (column 8, lines 3-20)

As can be seen by these cited sections, Ozawa discloses obtaining an approximate line from a relation of a position in the Y direction to the average value corresponding to the position in the Y direction and testing the device surface with a fluctuation obtained from the approximate line and the average value (i.e. forming the approximate line using the average value and determining a fluctuation/peak in the approximate line for testing the device surface).

### Applicant argues:

The Official Action has not shown that Ozawa is in the field of applicant's endeavor or that Ozawa is reasonably pertinent to the particular problem with which the Applicant is concerned. Specifically, the Applicant respectfully submits that a positioning method for a magnetic head body for a hard disk device is not reasonably pertinent to Tsumura or Tanaka or the features of the present invention, and the Official Action has not demonstrated why one of ordinary skill in the art at the time of the present invention would have necessarily looked to Ozawa in order to improve Tsumura or Tanaka.

## Ozawa discloses:

The present invention relates to a boundary line detecting method for specifying, by image processing, a boundary line between areas different in reflected light intensity, as well as a positioning method and apparatus for positioning, using the detecting method, for example a magnetic head body for a hard disk device and a support member such as a load beam relative to each other. (column 1, lines 11-17)

Therefore, while Ozawa does mention magnetic head positioning, Ozawa's disclosure focuses on solving the problem of detecting areas of a surface using differences in reflected light intensity. Such a disclosure is reasonably pertinent to the disclosure of Applicant's specification, Tsumura, and Tanaka.

EXAMSNER - AV 2857